



# **SNS COLLEGE OF TECHNOLOGY**

**Coimbatore-35**  
**An Autonomous Institution**



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Approved by AICTE, New Delhi & Affiliated to Anna University, Chennai

## **DEPARTMENT OF ELECTRONICS & COMMUNICATION ENGINEERING**

### **19ECB302–VLSI DESIGN**

III YEAR/ V SEMESTER

### **UNIT 4 –VLSI TESTING**

**TOPIC 4: Design Strategies -BIST & BOUNDARY SCAN**



# OUTLINE



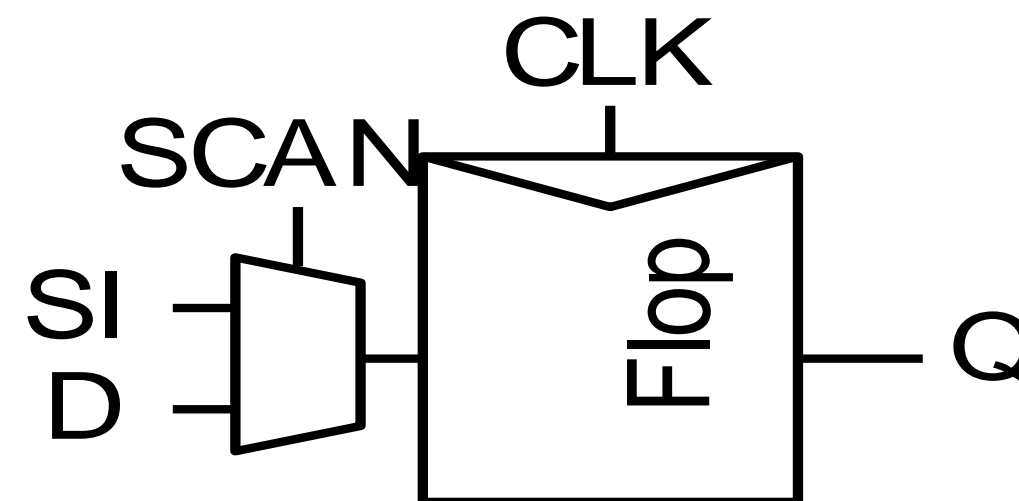
- Design for Test
  - Scan-FLIPFLOP
  - BIST
  - PRSG
  - BILBOActivity
- Boundary Scan
  - Examples
  - Interface summary



# DESIGN FOR TEST



- Design the chip to increase observability and controllability
- If each register could be observed and controlled, test problem reduces to testing combinational logic between registers.
- Better yet, logic blocks could enter test mode where they generate test patterns and report the results automatically.

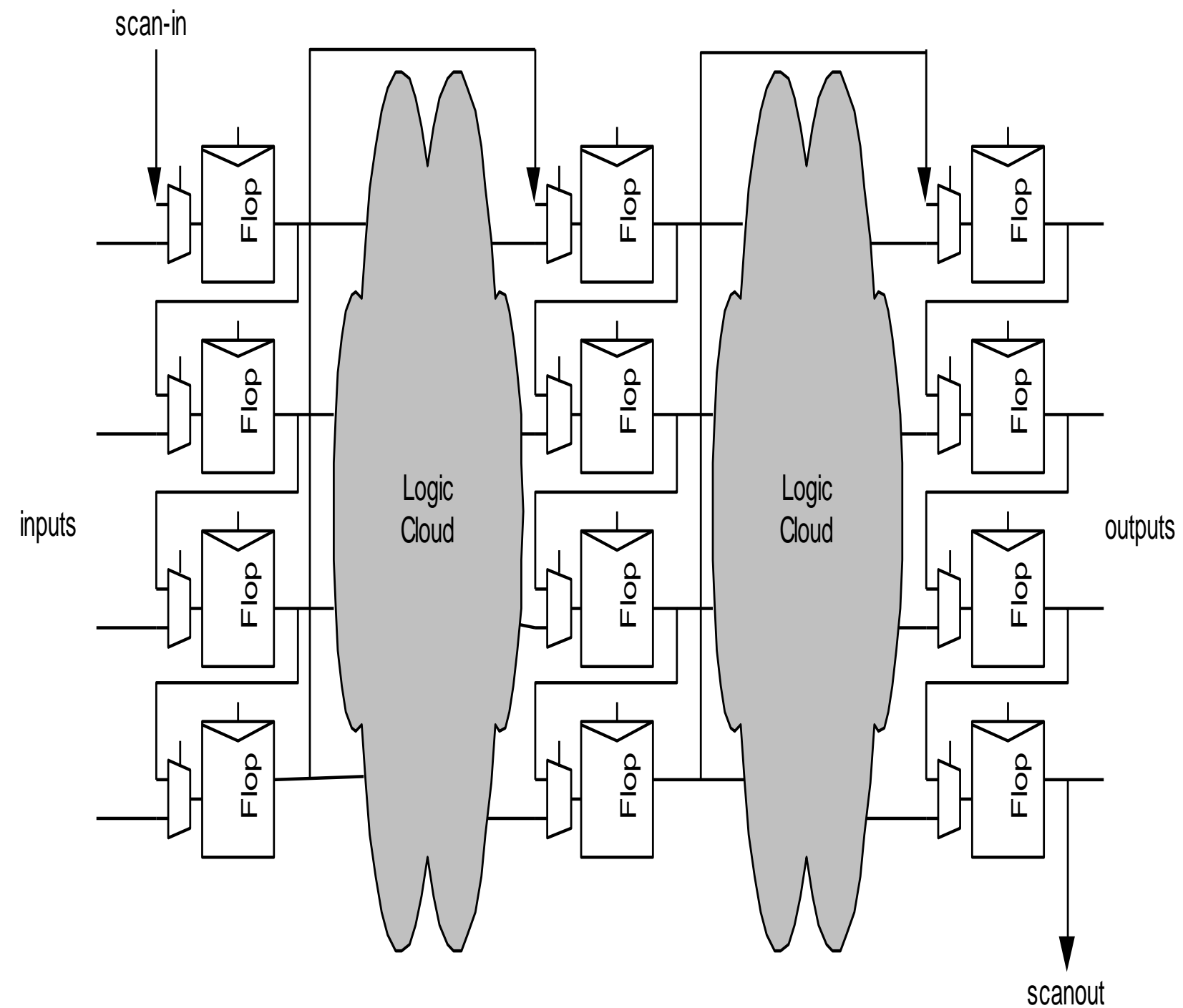




# SCAN

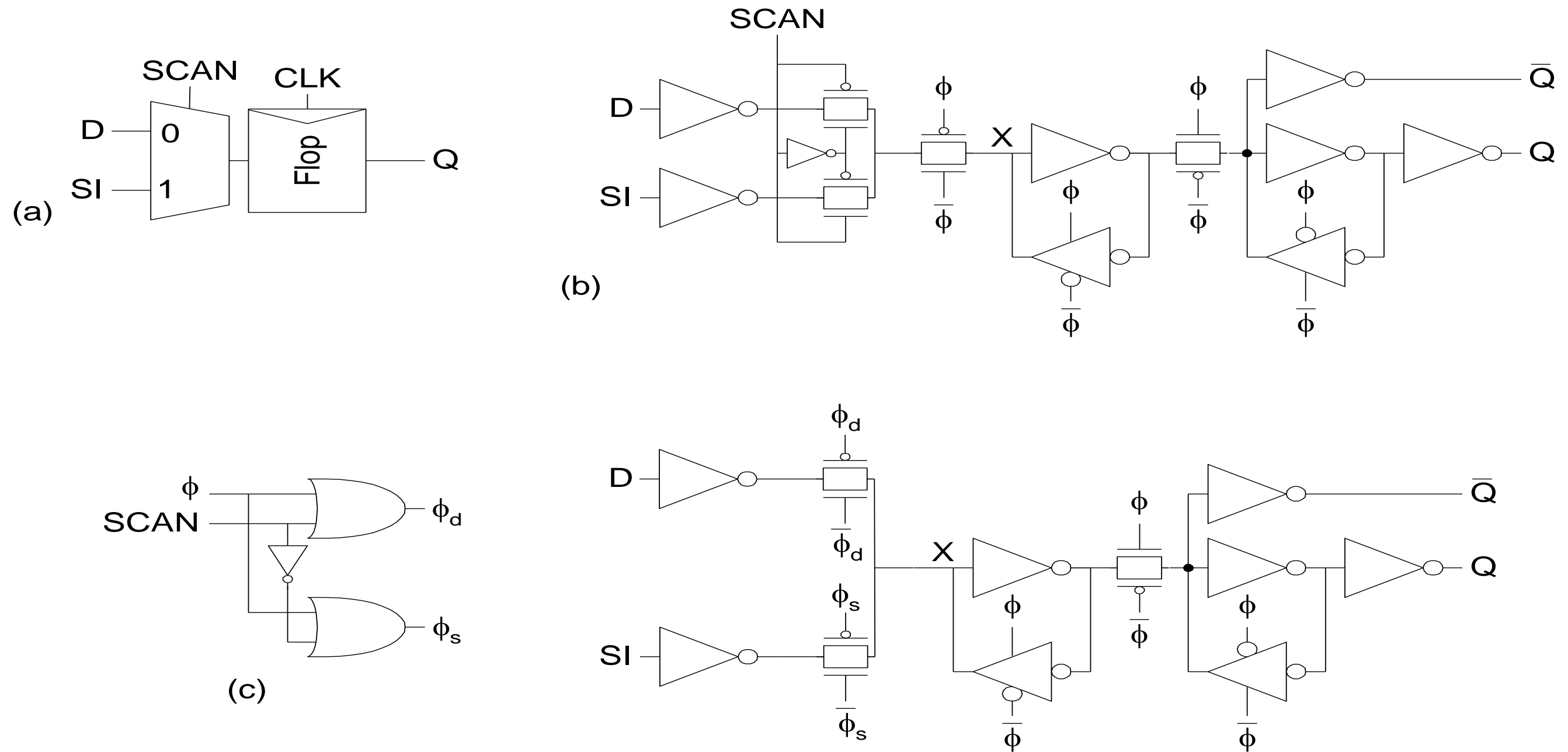


- Convert each flip-flop to a scan register
  - Only costs one extra multiplexer
- Normal mode: flip-flops behave as usual
- Scan mode: shift register
- Contents of flops can be scanned out and new values scanned in





# SCANNABLE FLIP-FLOPS



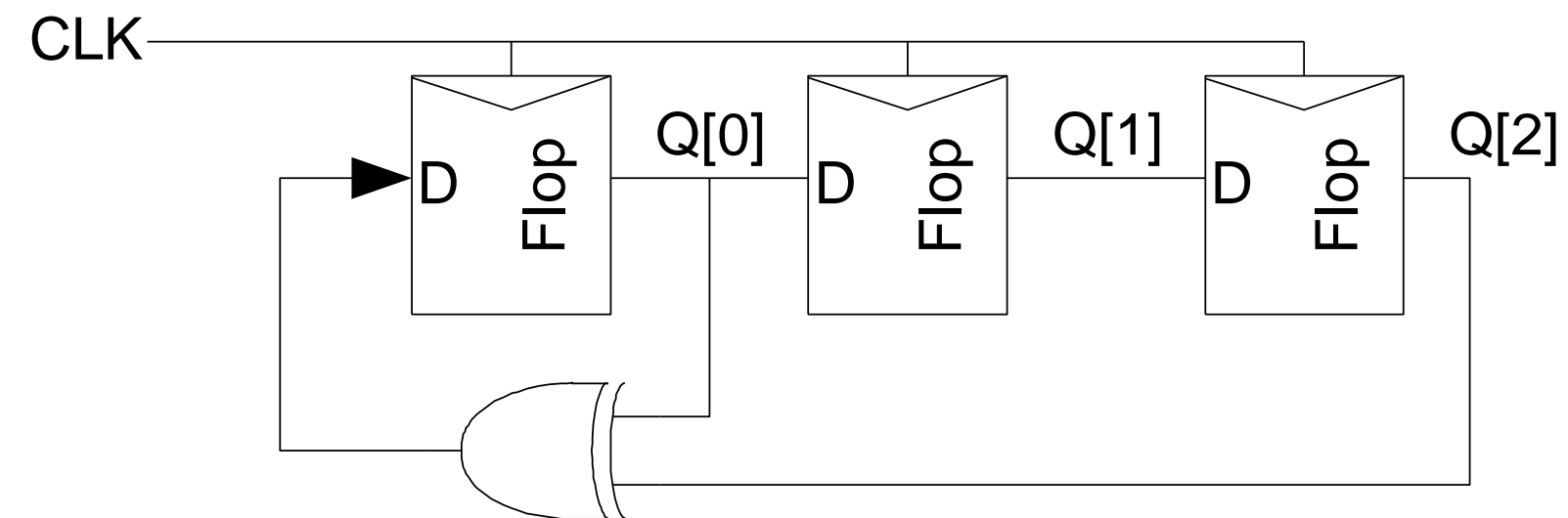


# BUILT-IN SELF-TEST



Built-in self-test lets blocks test themselves

Generate pseudo-random inputs to comb. Logic. Combine outputs into a syndrome With high probability, block is fault-free if it produces the expected syndrome.





# PRSG



- Linear Feedback Shift Register
  - Shift register with input taken from XOR of state
  - Pseudo-Random Sequence Generator

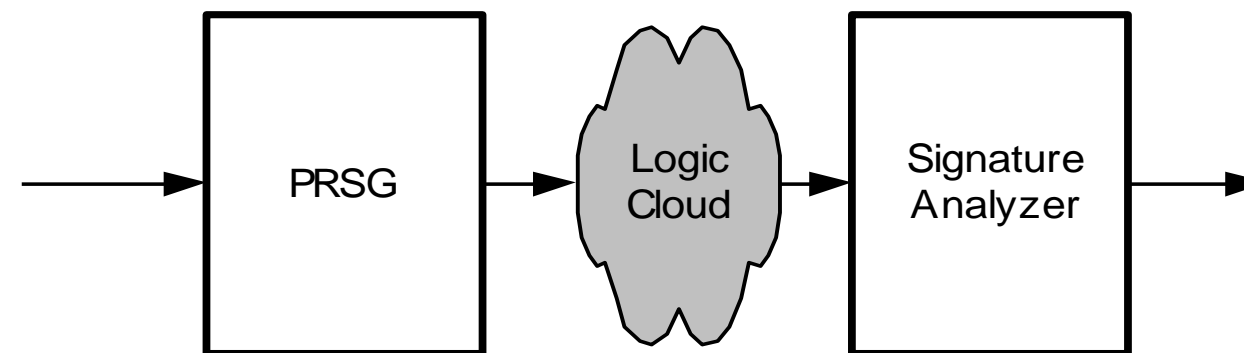
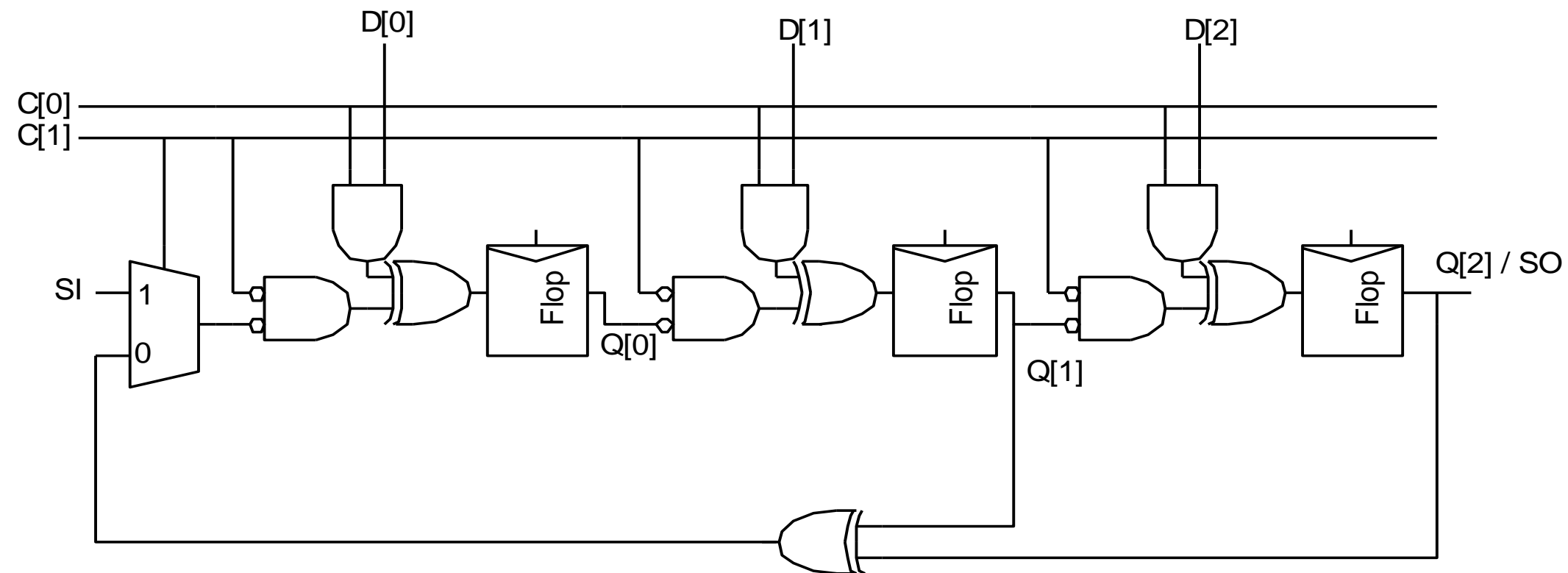
Step	Q
0	111
1	110
2	101
3	010
4	100
5	001
6	011
7	111 (repeats)



# BILBO



- Built-in Logic Block Observer
  - Combine scan with PRSG & signature analysis



MODE	C[1]	C[0]
Scan	0	0
Test	0	1
Reset	1	0
Normal	1	1





# ACTIVITY



## DEBATE : BOYS VS GIRLS

11/29/2022



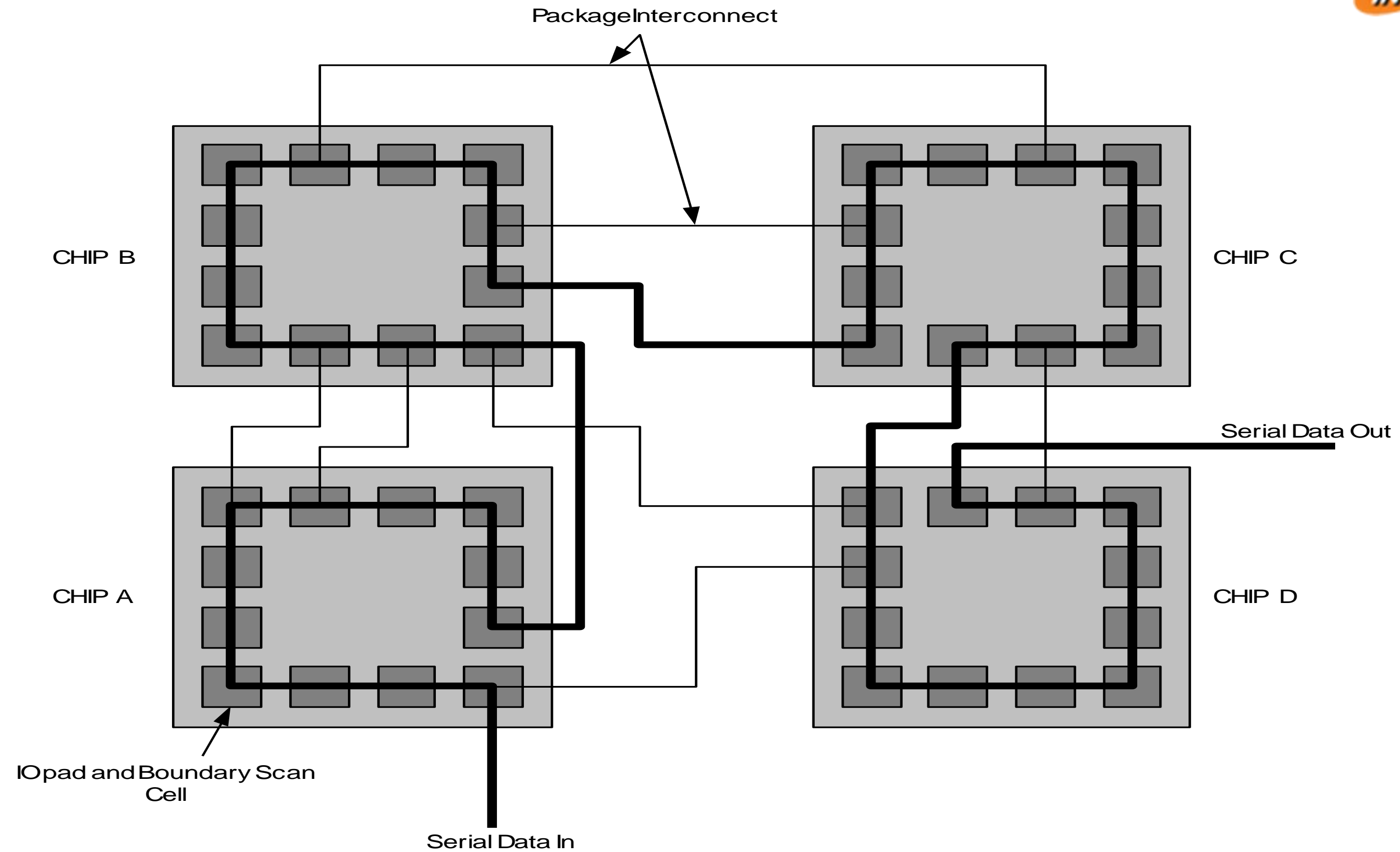
# BOUNDARY SCAN



- Testing boards is also difficult
  - Need to verify solder joints are good
    - Drive a pin to 0, then to 1
    - Check that all connected pins get the values
- Through-hole boards used “bed of nails”
- SMT and BGA boards cannot easily contact pins
- Build capability of observing and controlling pins into each chip to make board test easier



# BOUNDARY SCAN EXAMPLE





# BOUNDARY SCAN INTERFACE

Boundary scan is accessed through five pins

<b>TCK:</b>	<b>test clock</b>
<b>TMS:</b>	<b>test mode select</b>
<b>TDI:</b>	<b>test data in</b>
<b>TDO:</b>	<b>test data out</b>
<b>TRST*:</b>	<b>test reset (optional)</b>

Chips with internal scan chains can access the chains through boundary scan for unified test strategy.

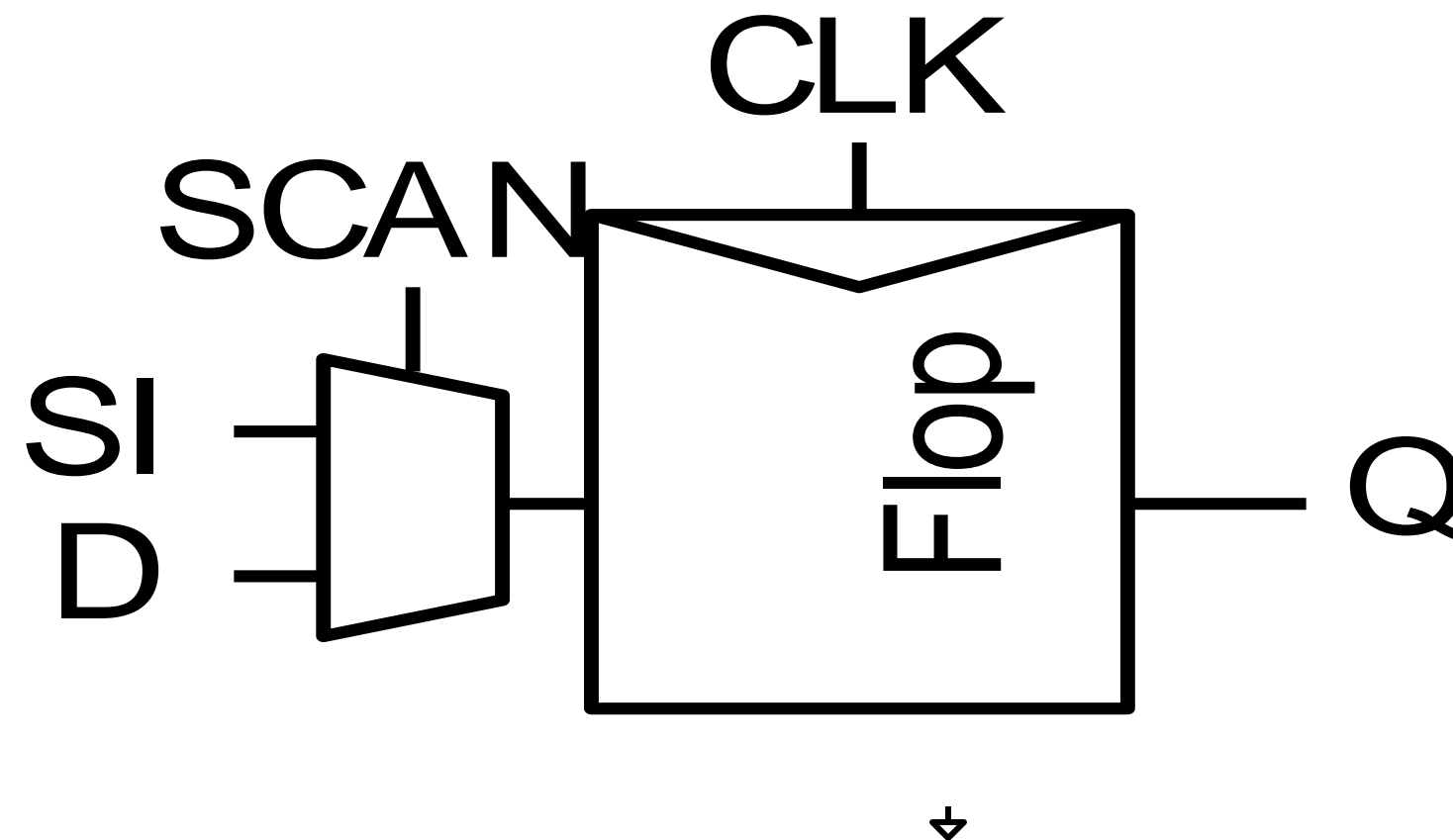


# SIMULATE



Think about testing from the beginning  
Simulate as you go  
Plan for test after fabrication

“If you don't test it, it won't work! (Guaranteed)”





# ASSESSMENT



WRITE THE BOUNDARY SCAN PIN NAMES  
& FILL UP THE BLANK IN PRSG

TABLE

TCK:

TMS:

TDI:

TDO:

TRST\*:

Step	Q
0	111
1	-----
2	101
3	-----
4	100
5	-----
6	011
7	-----





## SUMMARY & THANK YOU